

# Reflectometry Measurements of Electron Density Profiles and Fluctuations in NSTX

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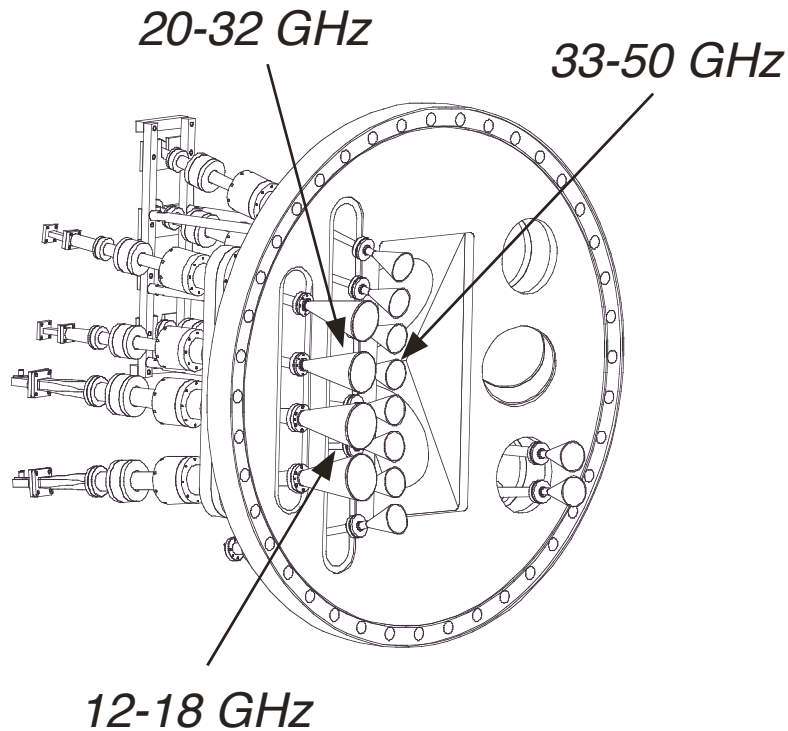
NSTX Results & Theory Review  
Princeton Plasma Physics Lab  
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# MM-Wave Reflectometry on NSTX: Goals and Contents

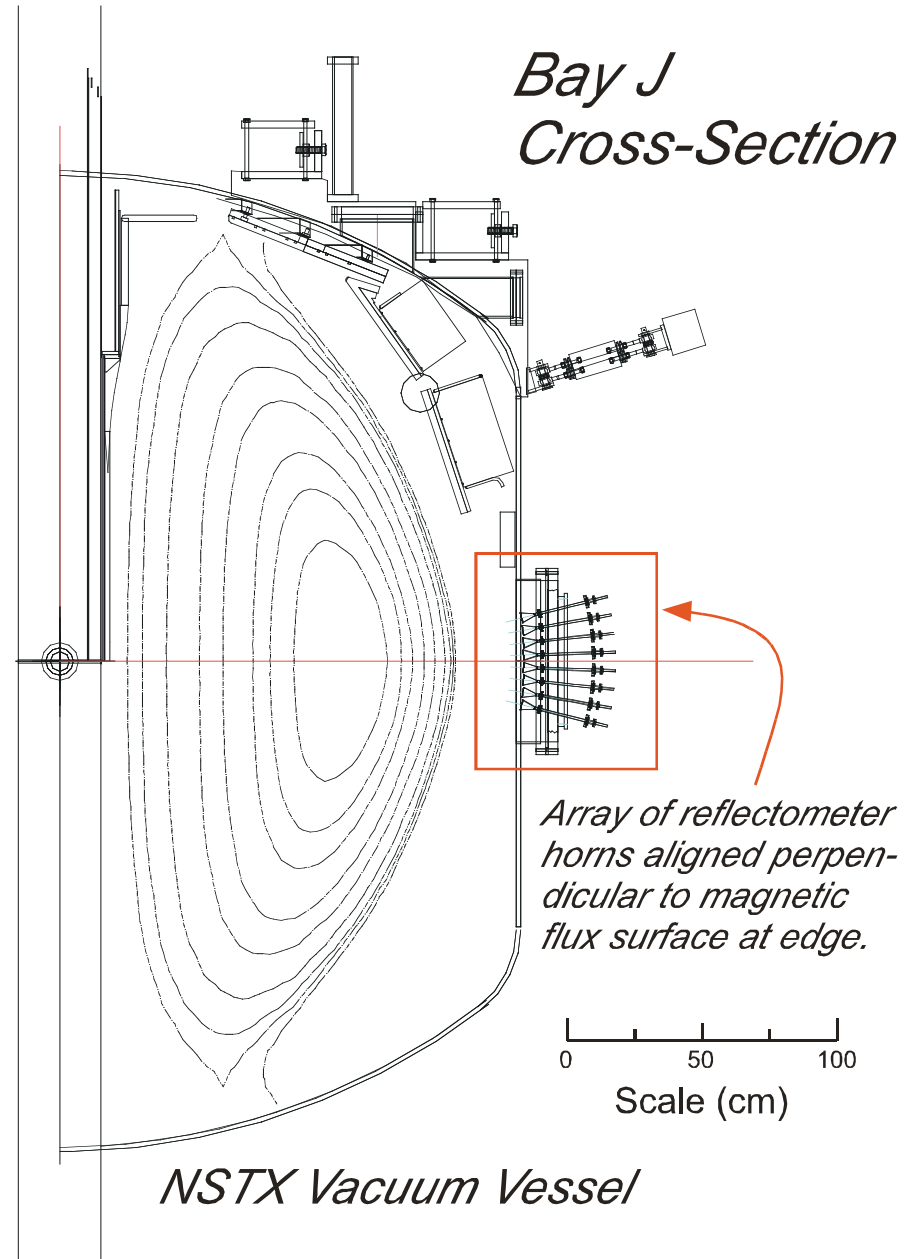


- ◆ Measurements of density profile and fluctuation quantities in region overlapping plasma edge and core.
  - Sensitive, local measurements with high bandwidth and excellent temporal coverage.
  - Density profiles, turbulent correlation length, fluctuation levels, magnetic field strength, Alfvén modes, etc.
  - Magnetic pitch angle, RF waves, etc.
- ◆ Density profile reconstruction.
  - Between-shot analysis, edge profile modeling, FY02 data.
  - Results from ELMy H-mode discharges.
- ◆ Fluctuation measurements.
  - Turbulence at L-H transition and during H-mode, ELMs.
- ◆ Compressional Alfvén eigenmodes.
  - Results from new fixed frequency quadrature systems. Simultaneous measurements of phase at three radial locations.

# Location of Reflectometer Diagnostics on Bay J



- ◆ Reflectometer uses 3 frequency bands:
  - 2 horns, 12-18 GHz.
  - 2 horns, 20-32 GHz.
  - 10 horns, 33-50 GHz.



*Bay J  
Cross-Section*

*Array of reflectometer horns aligned perpendicular to magnetic flux surface at edge.*

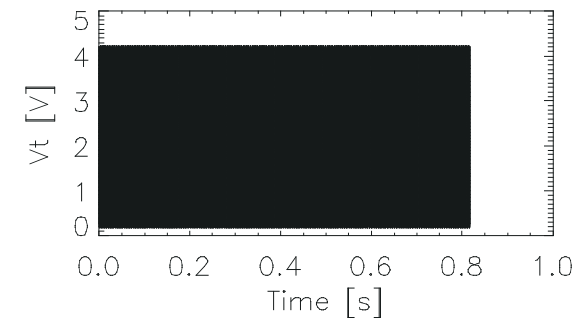
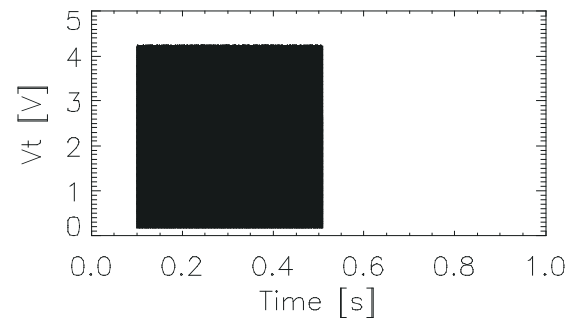
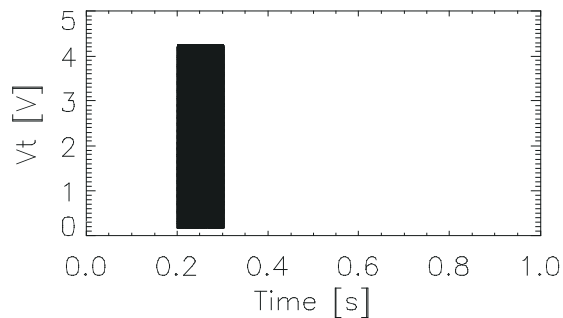
0 50 100  
Scale (cm)

*NSTX Vacuum Vessel*

# MM-Wave Reflectometer Capabilities



- ◆ Swept-frequency operation:  $T=100/400/800$  ms at  $\Delta t=0.1/0.5/1.0$  ms.



- ◆ Fixed/stepped-frequency: 3 synchronized channels,  $T=400/800$  ms at 10/5 MHz.
  - 12-50 GHz coverage using three bands ( $1.8 \times 10^{12}$  to  $3.1 \times 10^{13}$  cm<sup>-3</sup>, O-mode).
  - Sweep over full band in 50  $\mu$ s (reduce to 10-20  $\mu$ s range).
  - To reduce turbulence effects 2 sweeps are averaged.  $\Delta t=100$   $\mu$ s.
  - 8 MSamples each shot or 1636/2 profiles per shot (increase to 4090/2 or 8180/2).
  - LabVIEW control - easy to use GUI. Acquisition sequence is programmable.
  - Can alternate between fixed and swept frequency operation shot-by-shot (alternate between swept and fixed frequency operation during single shot).
  - Mode/polarization needs to be set manually in test cell.
  - PC data acquisition uses  $t=0$  trigger, but not synchronized to facility clock.

# Status of Diagnostic System/Profile Analysis



- ◆ Profile reflectometer has been acquiring data routinely. About 1000 shots for FY02.
- ◆ Analysis is multiple-step process involving 1) signal processing, 2) averaging and smoothing over turbulence effects, 3) **edge modeling**, 4) profile inversion.
- ◆ Single shot requires ~30 minutes for steps 1) and 2). This has been completed for FY02 data. Inverted profiles analyzed for May and June 2002. Will be made available on bulk storage first.
- ◆ Issue:
  - Largest uncertainties (position, gradient) due to edge modeling below lowest cutoff density ( $1.8 \times 10^{12} \text{ cm}^{-3}$ ). Edge modeling using Thomson scattering edge data simplifies analysis greatly, but ... (In collaboration with EBW group, plans for 4-18 GHz system.)

# Density Profile Reconstruction



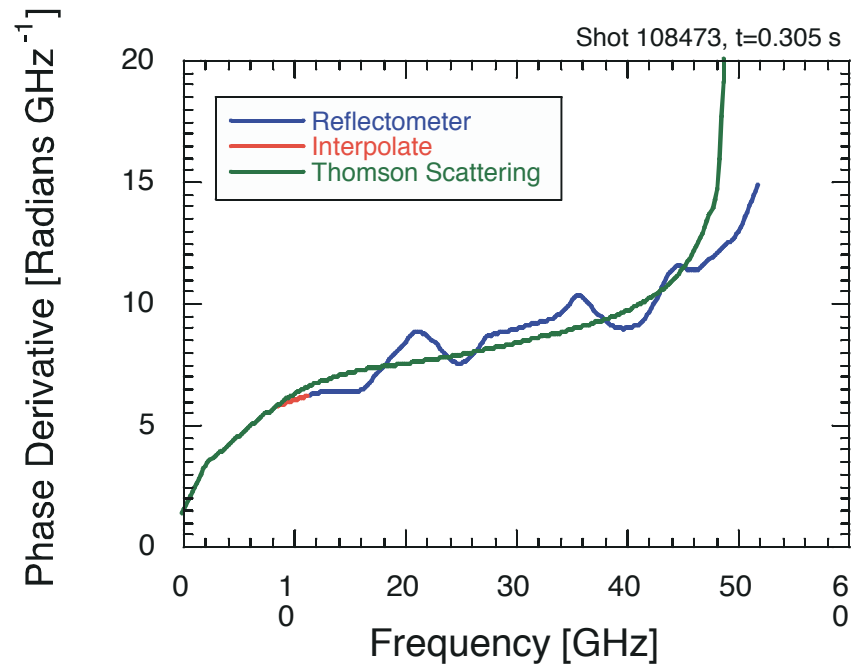
$$\varphi_p(f) = \frac{4\pi f}{c} \int_{r_c(f)}^{r_p} n(r, f) dr - \frac{\pi}{2}$$

$\varphi_p(f)$  phase shift of reflected wave

$n(r, f)$  plasma index of refraction

$r_p$  plasma start position

$r_c(f)$  cutoff layer at frequency  $f$



For O-mode, equation for phase curve can be written:

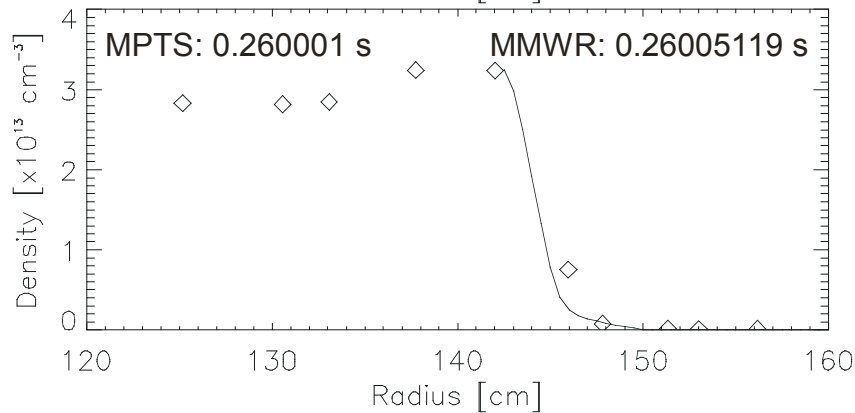
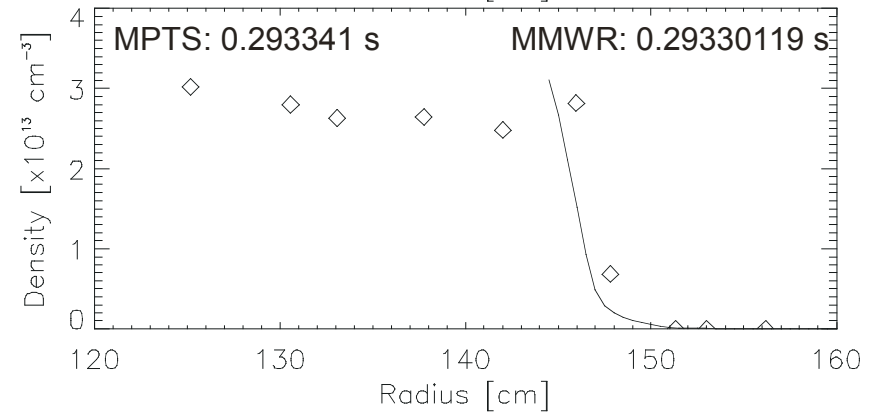
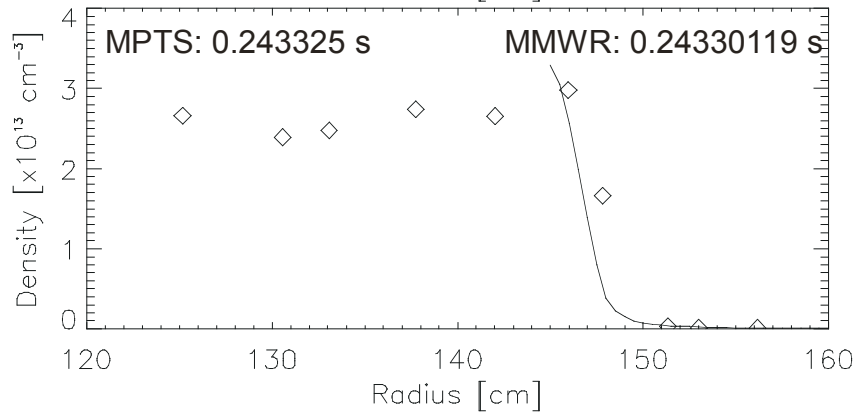
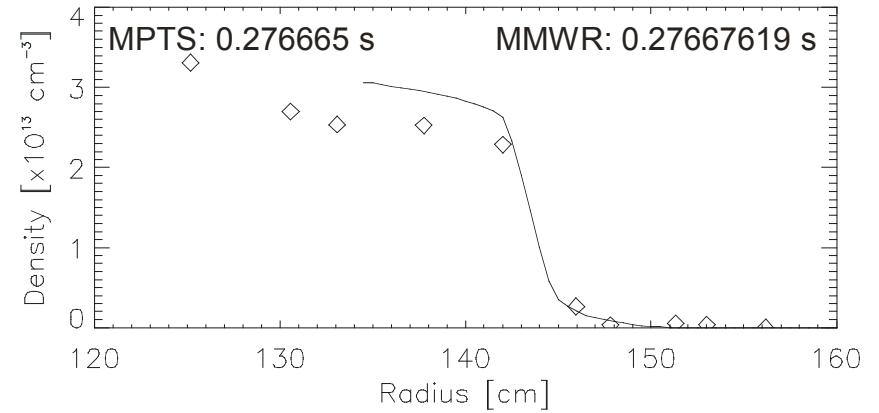
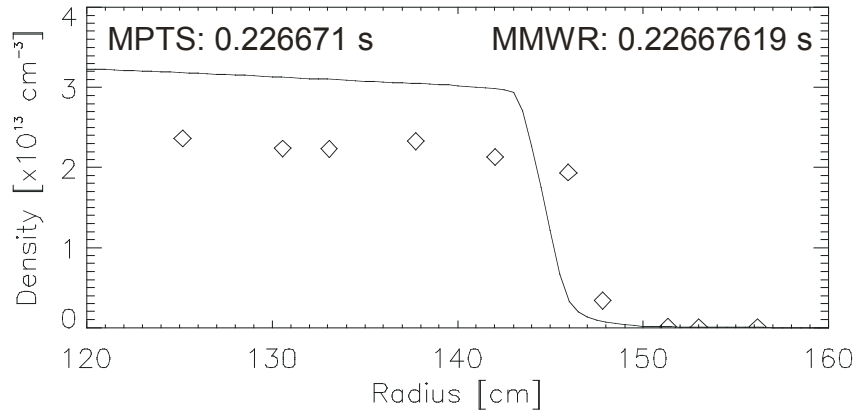
$$\varphi = \mathbf{M} \cdot r$$

Then  $r$  is recovered via

$$r = \mathbf{M}^{-1} \cdot \varphi$$

- ◆ Edge portion of phase curve required for density profile reconstruction.
- ◆ Modeled edge influences position of cutoff layer and gradient (influence largest at edge and decreases inward).
- ◆ Using edge points from Thomson scattering 20 pt data significantly decreases amount of computation.

# Comparison with Thomson Scattering (Shot 108487)

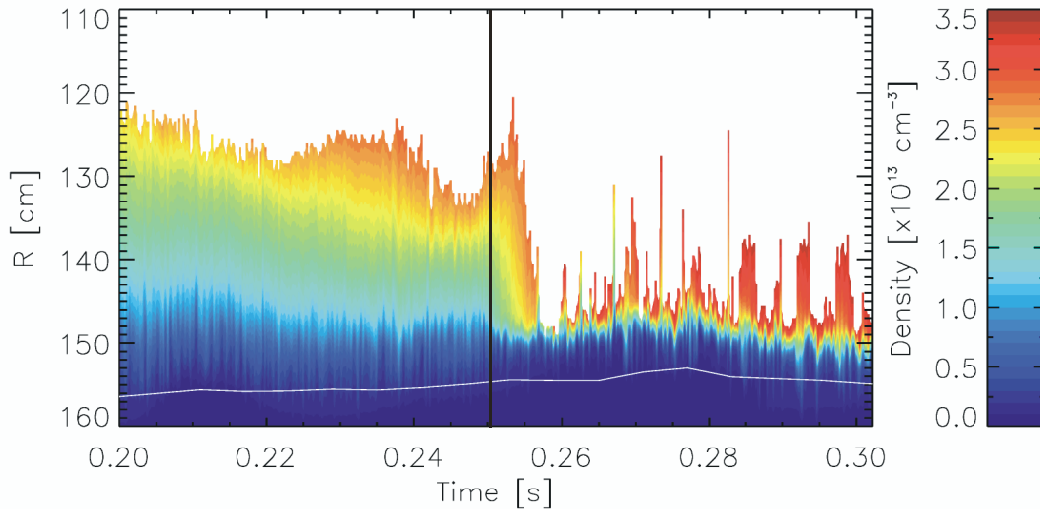


- ◆ Using spline fit to Thomson edge profile below  $n_e = 9 \times 10^{11} \text{ cm}^{-3}$ .
- ◆ Typical discrepancy of less than 2 cm between reflectometry and Thomson scattering profiles.
- ◆ Spatial resolution of  $< 5 \text{ mm}$ .

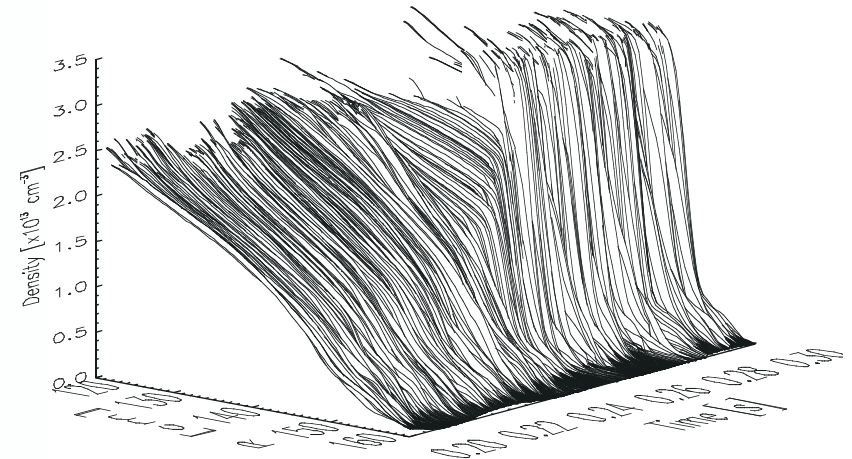
# NB-Heated Discharge: L- to H-Mode Transition (Shot 108470)



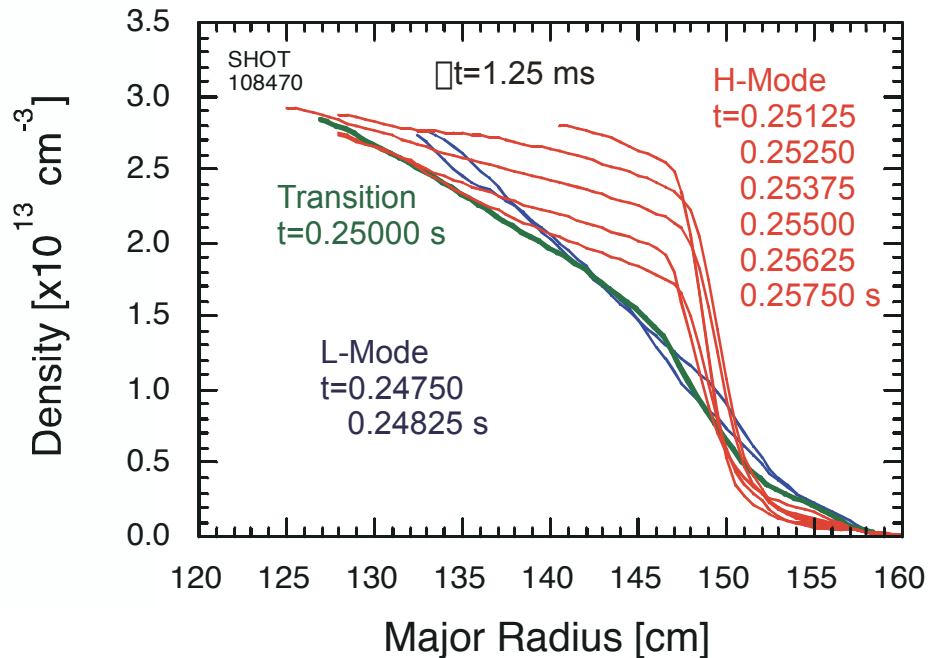
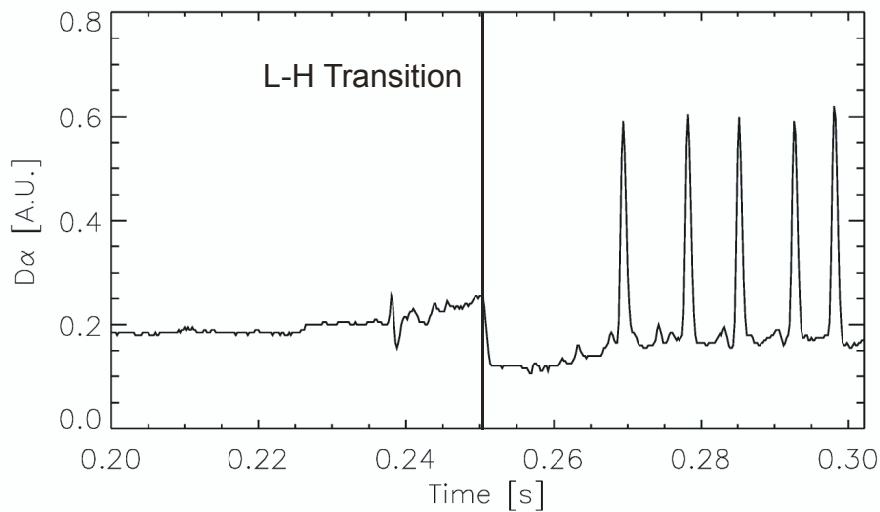
Shot 108470, Density Profile Contour Plot



Density Profile Surface Plot ( $t=0.200-0.300$  s)



Shot 108470, Bay C  $D\alpha$  Intensity (Lower Divertor)

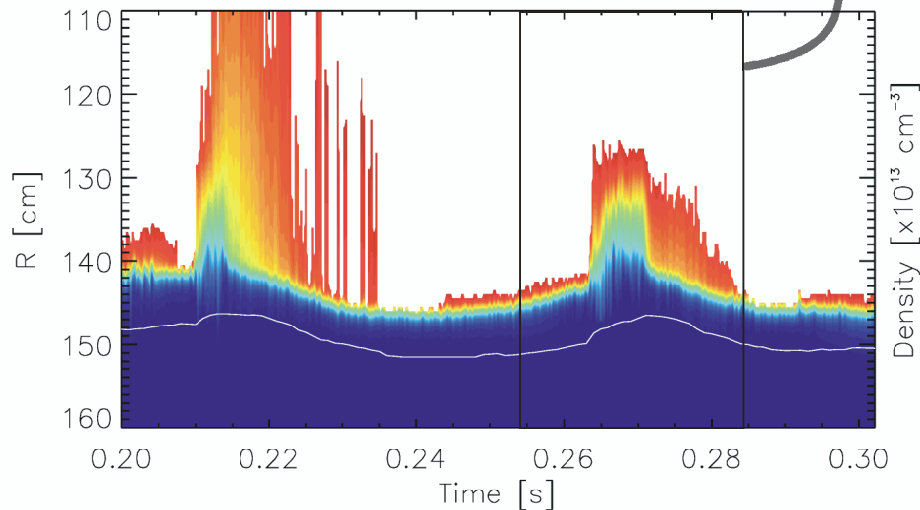




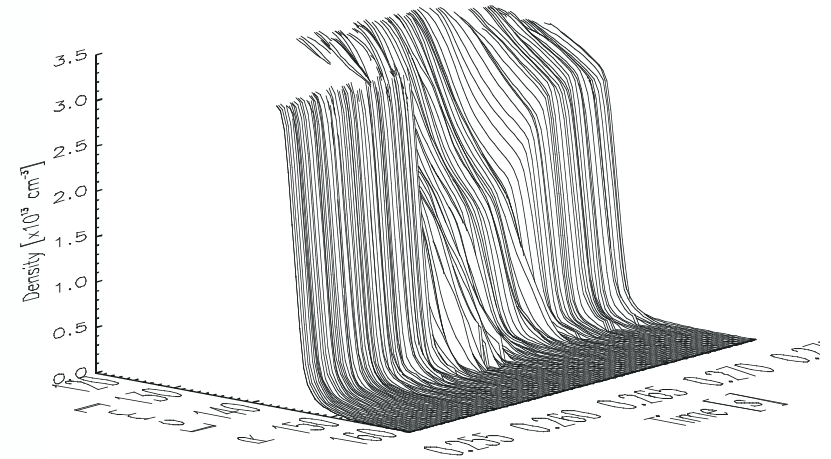
# NB-Heated Discharge: H-Mode, Giant ELMs (Shot 108487)



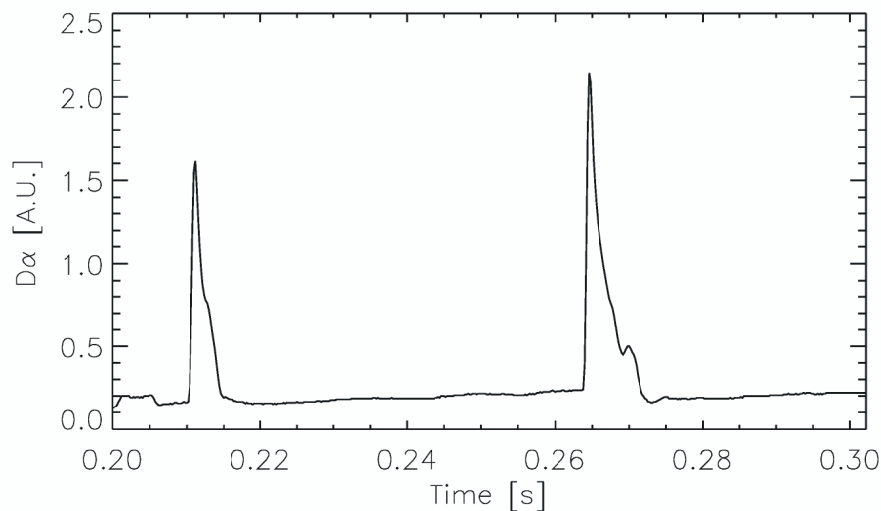
Shot 108487, Density Profile Contour Plot



Density Profile Surface Plot (t=0.255-0.275 s)



Shot 108487, Bay C D $\alpha$  Intensity (Lower Divertor)

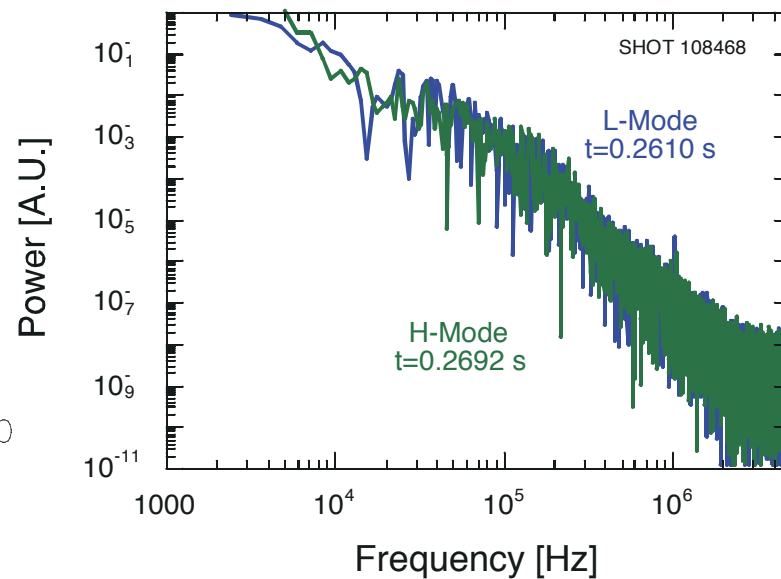
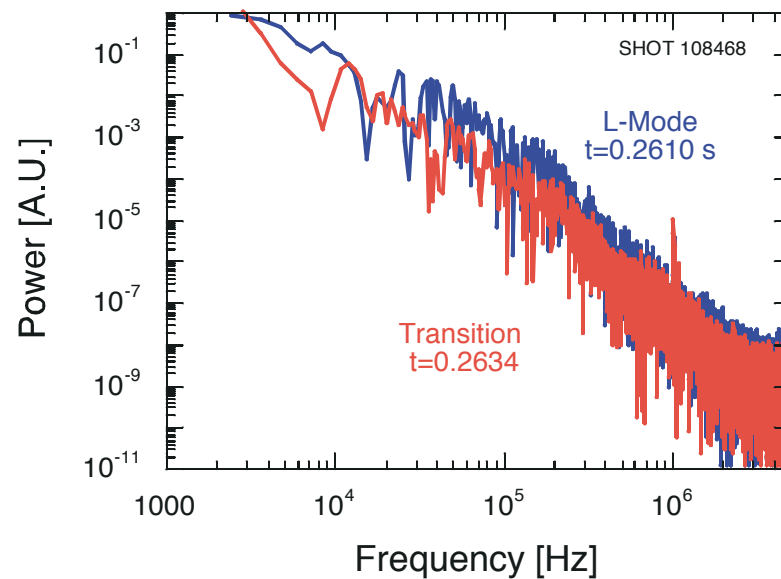
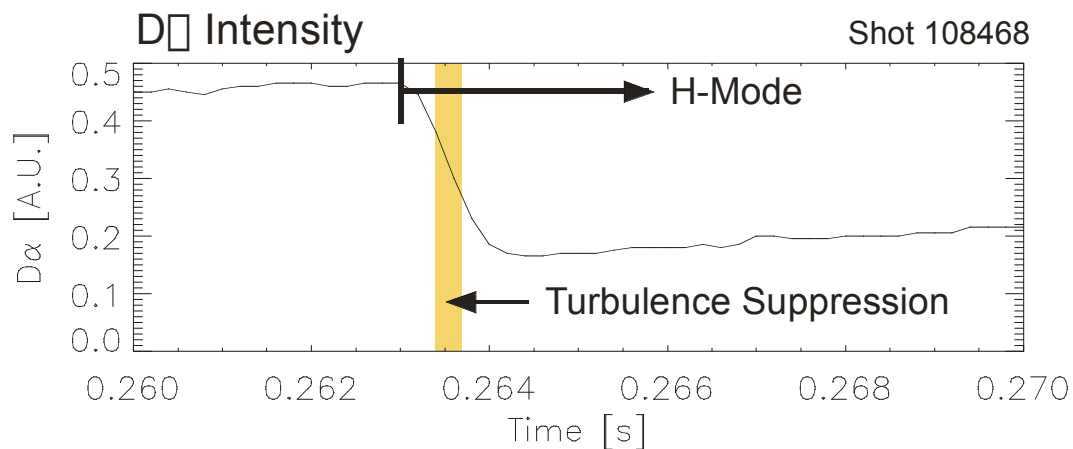
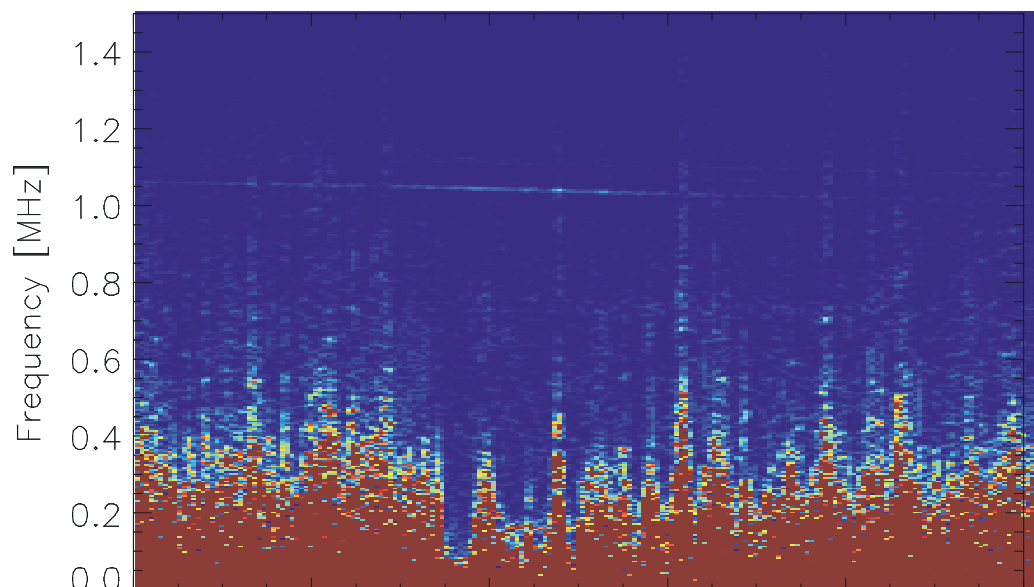


- ◆ Density contour tracks with EFIT01 LCFS very well.
- ◆ Rapid changes (fluctuations) in density profile with onset of ELMs.  $\Delta t=100$   $\mu$ s not fast enough to catch evolution.
- ◆ Fast ELM-like profile changes seen without corresponding D $\alpha$  signature.
- ◆ Looking into decreasing sweep time to  $\sim 10$   $\mu$ s.

# Turbulence Suppression/Fluctuations at L-H Transition



Spectrogram of Phase,  $f=16.8$  GHz ( $3.5 \times 10^{12}$  cm $^{-3}$ )

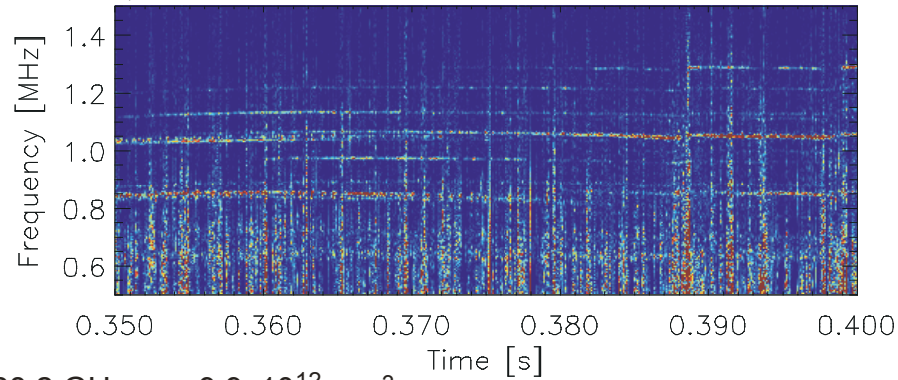


# Fluctuation Measurements: Compressional Alfvén Eigenmodes

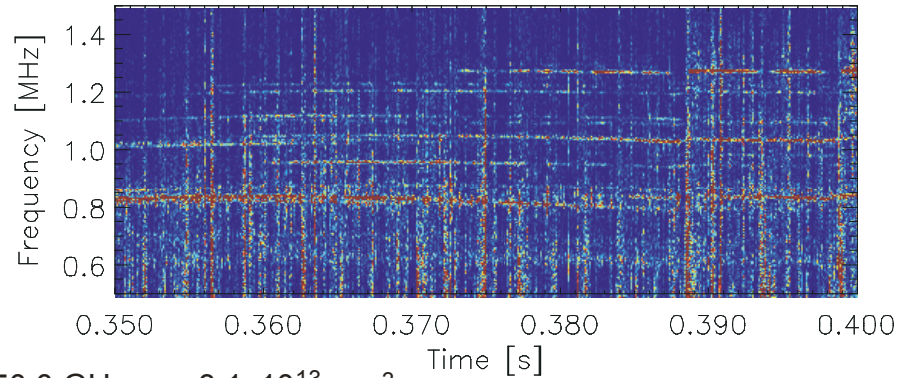


## Shot 108824, Reflectometer Phase Spectrograms

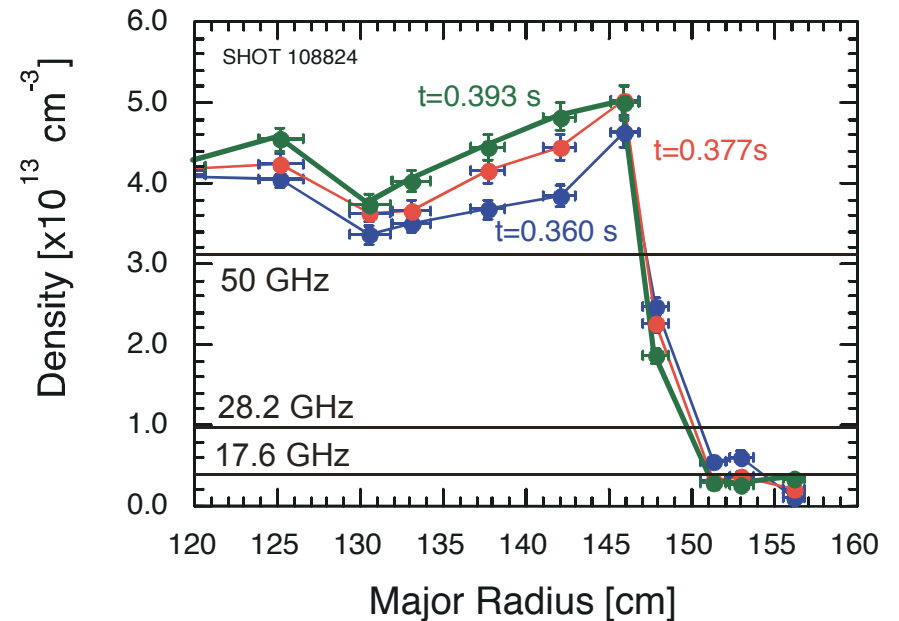
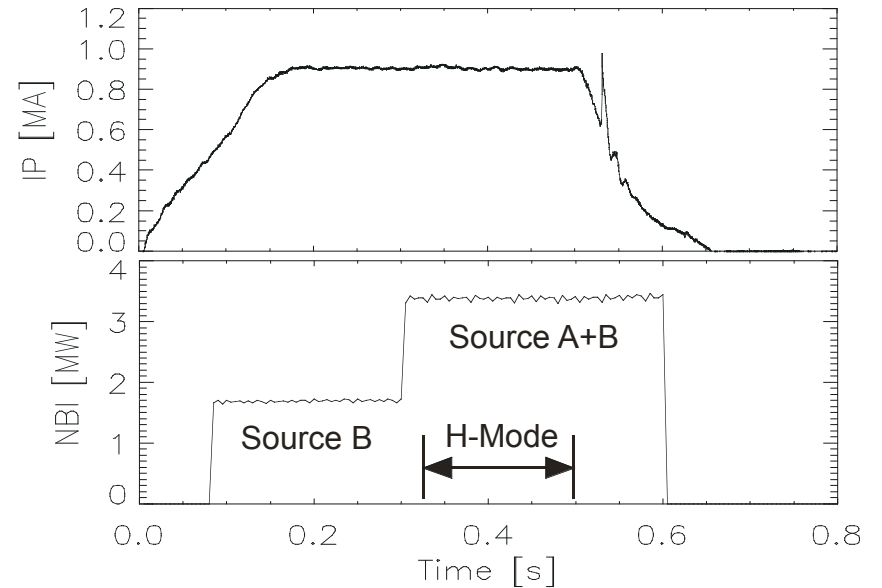
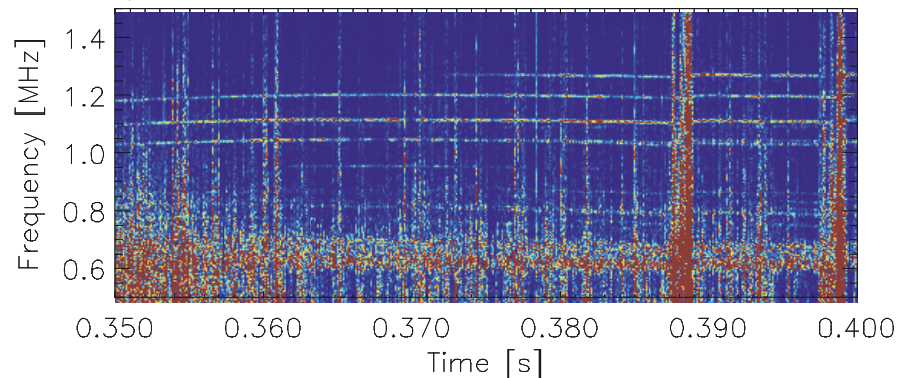
f=17.6 GHz,  $n_e=3.8 \times 10^{12} \text{ cm}^{-3}$



f=28.2 GHz,  $n_e=9.9 \times 10^{12} \text{ cm}^{-3}$



f=50.0 GHz,  $n_e=3.1 \times 10^{13} \text{ cm}^{-3}$



# Concluding Remarks



- ◆ Synchronous measurements at three radial locations of  $\langle n \rangle$  due to CAEs: Analysis goal:  $\langle n \rangle / n \sim \langle B_{\parallel} \rangle / B$  (Fredrickson, Gorelenkov, Kramer). Spatial points sufficient?
- ◆ Profile analysis software runs automatically. Batch analysis using petrel cluster. Between-shot analysis is possible if network and multiple dedicated CPUs are available.
- ◆ Inverted profiles analyzed for May and June 2002 data for shots with 20 point Thomson data (edge modeling). Should be trivial inverting remaining shots. Uncertainty?
- ◆ Where is data? Problems with running Unix and accessing VAX storage